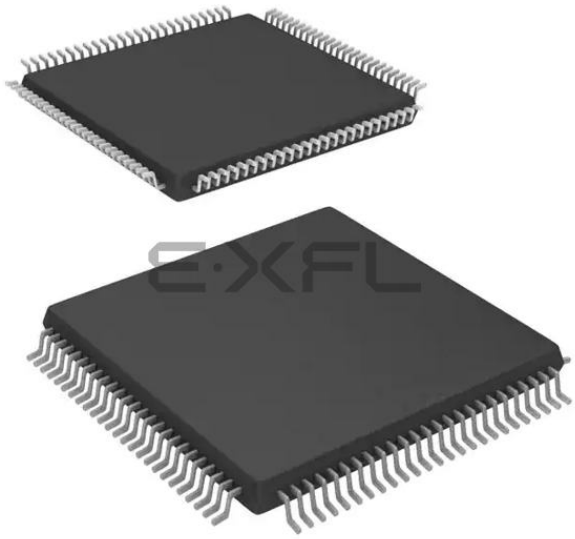


Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	8051
Core Size	8-Bit
Speed	50MHz
Connectivity	EBI/EMI, I²C, LINbus, SPI, UART/USART
Peripherals	CapSense, DMA, POR, PWM, WDT
Number of I/O	62
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3245axi-158

More Information

Cypress provides a wealth of data at www.cypress.com to help you to select the right PSoC device for your design, and to help you to quickly and effectively integrate the device into your design. For a comprehensive list of resources, see the knowledge base article KBA86521, How to Design with PSoC 3, PSoC 4, and PSoC 5LP. Following is an abbreviated list for PSoC 3:

- Overview: PSoC Portfolio, PSoC Roadmap
- Product Selectors: PSoC 1, PSoC 3, PSoC 4, PSoC 5LP
  In addition, PSoC Creator includes a device selection tool.
- Application notes: Cypress offers a large number of PSoC application notes and code examples covering a broad range of topics, from basic to advanced level. Recommended application notes for getting started with PSoC 3 are:
  - AN54181: Getting Started With PSoC 3
  - AN61290: Hardware Design Considerations
  - AN57821: Mixed Signal Circuit Board Layout
  - AN58304: Pin Selection for Analog Designs
  - AN81623: Digital Design Best Practices
  - AN73854: Introduction To Bootloaders
- Development Kits:
  - CY8CKIT-030 is designed for analog performance, for developing high-precision analog, low-power, and low-voltage applications.
  - CY8CKIT-001 provides a common development platform for any one of the PSoC 1, PSoC 3, PSoC 4, or PSoC 5LP families of devices.
  - The MiniProg3 device provides an interface for flash programming and debug.
- Technical Reference Manuals (TRM)
  - Architecture TRM
  - Registers TRM
  - Programming Specification

PSoC Creator

PSoC Creator is a free Windows-based Integrated Design Environment (IDE). It enables concurrent hardware and firmware design of PSoC 3, PSoC 4, and PSoC 5LP based systems. Create designs using classic, familiar schematic capture supported by over 100 pre-verified, production-ready PSoC Components; see the list of component datasheets. With PSoC Creator, you can:

1. Drag and drop component icons to build your hardware system design in the main design workspace
2. Codesign your application firmware with the PSoC hardware, using the PSoC Creator IDE C compiler
3. Configure components using the configuration tools
4. Explore the library of 100+ components
5. Review component datasheets

Figure 1. Multiple-Sensor Example Project in PSoC Creator

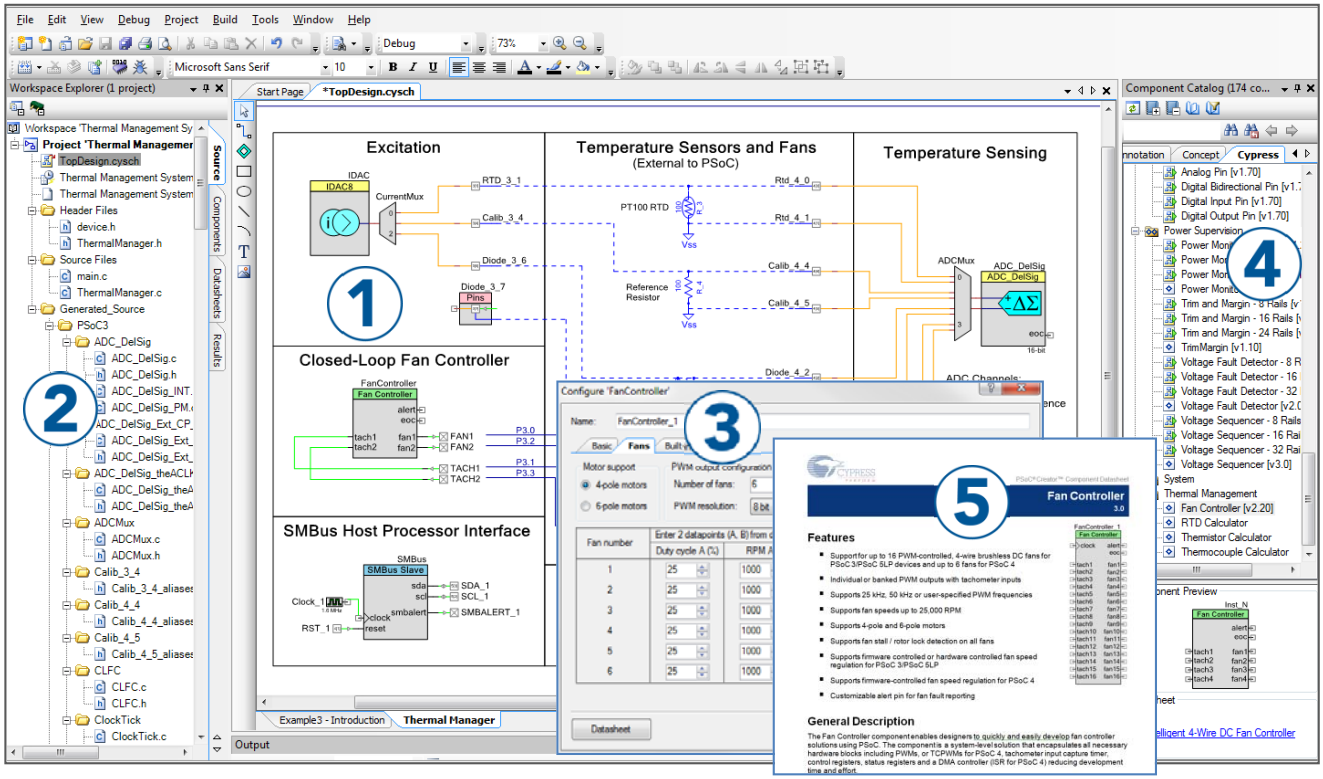
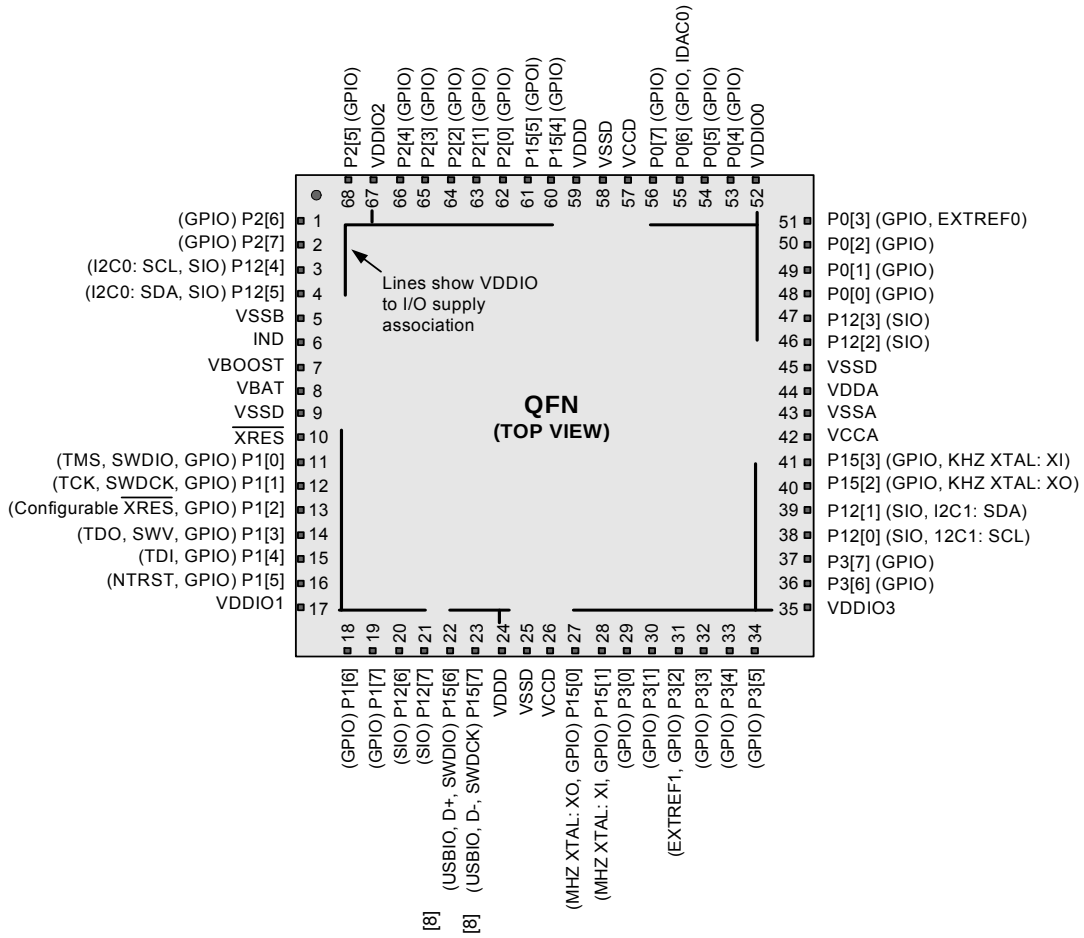


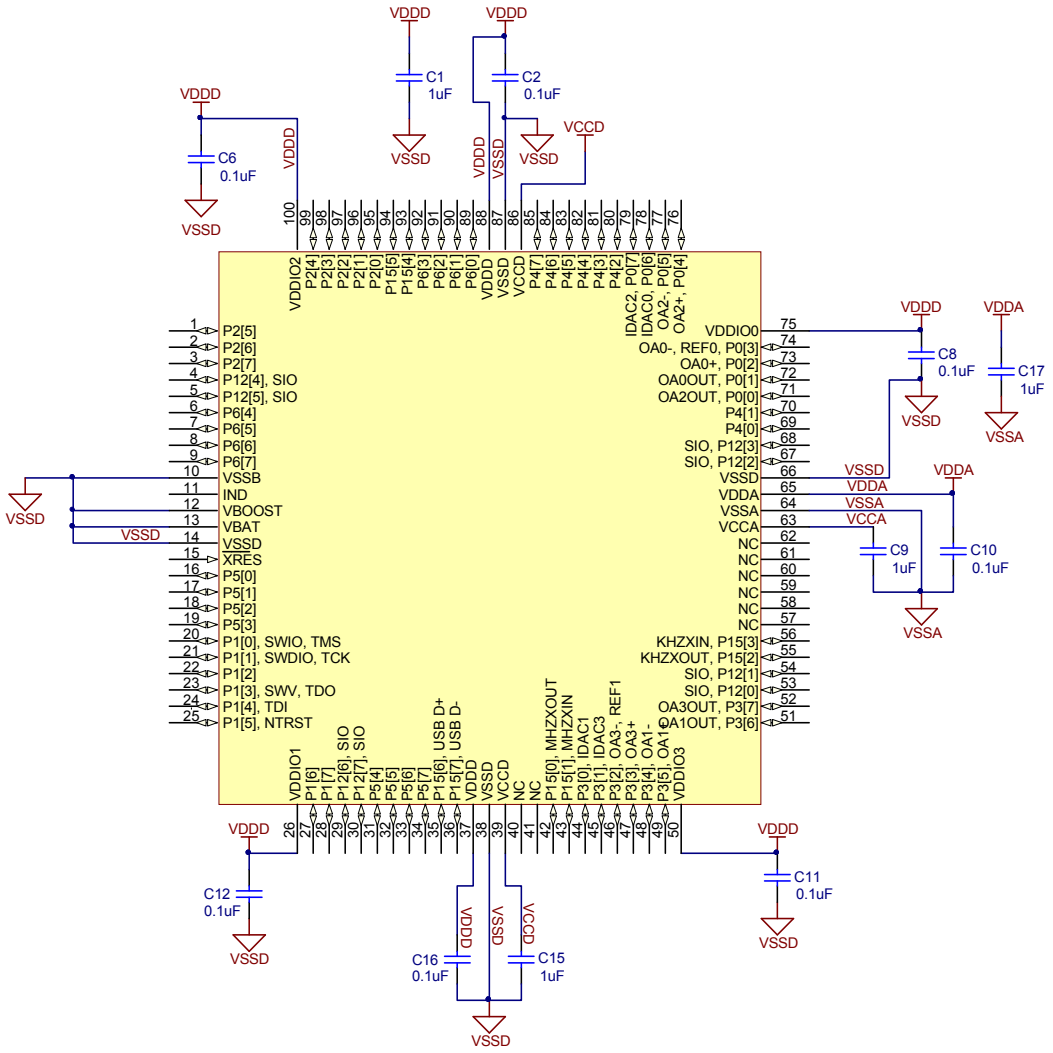
Figure 2-5. 68-pin QFN Part Pinout[7]



Notes

7. The center pad on the QFN package should be connected to digital ground (VSSD) for best mechanical, thermal, and electrical performance. If not connected to ground, it should be electrically floated and not connected to any other signal. For more information, see AN72845, Design Guidelines for QFN Devices.
8. Pins are Do Not Use (DNU) on devices without USB. The pin must be left floating.

Figure 2-7. Example Schematic for 100-pin TQFP Part with Power Connections



Note The two VCCD pins must be connected together with as short a trace as possible. A trace under the device is recommended, as shown in Figure 2-8 on page 12.

For more information on pad layout, refer to http://www.cypress.com/cad-resources/psoc-3-cad-libraries.

4.4.4.5 Scatter Gather DMA

In the case of scatter gather DMA, there are multiple noncontiguous sources or destinations that are required to effectively carry out an overall DMA transaction. For example, a packet may need to be transmitted off of the device and the packet elements, including the header, payload, and trailer, exist in various noncontiguous locations in memory. Scatter gather DMA allows the segments to be concatenated together by using multiple TDs in a chain. The chain gathers the data from the multiple locations. A similar concept applies for the reception of data onto the device. Certain parts of the received data may need to be scattered to various locations in memory for software processing convenience. Each TD in the chain specifies the location for each discrete element in the chain.

4.4.4.6 Packet Queuing DMA

Packet queuing DMA is similar to scatter gather DMA but specifically refers to packet protocols. With these protocols, there may be separate configuration, data, and status phases associated with sending or receiving a packet.

For instance, to transmit a packet, a memory mapped configuration register can be written inside a peripheral, specifying the overall length of the ensuing data phase. The CPU can set up this configuration information anywhere in system memory and copy it with a simple TD to the peripheral. After the configuration phase, a data phase TD (or a series of data phase TDs) can begin (potentially using scatter gather). When the data phase TD(s) finish, a status phase TD can be invoked that reads some memory mapped status information from the peripheral and copies it to a location in system memory specified by the CPU for later inspection. Multiple sets of configuration, data, and status phase “subchains” can be strung together to create larger chains that transmit multiple packets in this way. A similar concept exists in the opposite direction to receive the packets.

4.4.4.7 Nested DMA

One TD may modify another TD, as the TD configuration space is memory mapped similar to any other peripheral. For example, a first TD loads a second TD’s configuration and then calls the second TD. The second TD moves data as required by the application. When complete, the second TD calls the first TD, which again updates the second TD’s configuration. This process repeats as often as necessary.

4.5 Interrupt Controller

The interrupt controller provides a mechanism for hardware resources to change program execution to a new address, independent of the current task being executed by the main code. The interrupt controller provides enhanced features not found on original 8051 interrupt controllers:

- Thirty two interrupt vectors
- Jumps directly to ISR anywhere in code space with dynamic vector addresses
- Multiple sources for each vector
- Flexible interrupt to vector matching
- Each interrupt vector is independently enabled or disabled
- Each interrupt can be dynamically assigned one of eight priorities
- Eight level nestable interrupts
- Multiple I/O interrupt vectors
- Software can send interrupts
- Software can clear pending interrupts

When an interrupt is pending, the current instruction is completed and the program counter is pushed onto the stack. Code execution then jumps to the program address provided by the vector. After the ISR is completed, a RETI instruction is executed and returns execution to the instruction following the previously interrupted instruction. To do this the RETI instruction pops the program counter from the stack.

If the same priority level is assigned to two or more interrupts, the interrupt with the lower vector number is executed first. Each interrupt vector may choose from three interrupt sources: Fixed Function, DMA, and UDB. The fixed function interrupts are direct connections to the most common interrupt sources and provide the lowest resource cost connection. The DMA interrupt sources provide direct connections to the two DMA interrupt sources provided per DMA channel. The third interrupt source for vectors is from the UDB digital routing array. This allows any digital signal available to the UDB array to be used as an interrupt source. Fixed function interrupts and all interrupt sources may be routed to any interrupt vector using the UDB interrupt source connections.

Figure 4-2 on page 21 represents typical flow of events when an interrupt triggered. Figure 4-3 on page 22 shows the interrupt structure and priority polling.

Table 4-8. Interrupt Vector Table

#	Fixed Function	DMA	UDB
0	LVD	phub_termout0[0]	udb_intr[0]
1	Cache/ECC	phub_termout0[1]	udb_intr[1]
2	Reserved	phub_termout0[2]	udb_intr[2]
3	Sleep (Pwr Mgr)	phub_termout0[3]	udb_intr[3]
4	PICU[0]	phub_termout0[4]	udb_intr[4]
5	PICU[1]	phub_termout0[5]	udb_intr[5]
6	PICU[2]	phub_termout0[6]	udb_intr[6]
7	PICU[3]	phub_termout0[7]	udb_intr[7]
8	PICU[4]	phub_termout0[8]	udb_intr[8]
9	PICU[5]	phub_termout0[9]	udb_intr[9]
10	PICU[6]	phub_termout0[10]	udb_intr[10]
11	PICU[12]	phub_termout0[11]	udb_intr[11]
12	PICU[15]	phub_termout0[12]	udb_intr[12]
13	Comparators Combined	phub_termout0[13]	udb_intr[13]
14	Reserved	phub_termout0[14]	udb_intr[14]
15	I^2C	phub_termout0[15]	udb_intr[15]
16	Reserved	phub_termout1[0]	udb_intr[16]
17	Timer/Counter0	phub_termout1[1]	udb_intr[17]
18	Timer/Counter1	phub_termout1[2]	udb_intr[18]
19	Timer/Counter2	phub_termout1[3]	udb_intr[19]
20	Timer/Counter3	phub_termout1[4]	udb_intr[20]
21	USB SOF Int	phub_termout1[5]	udb_intr[21]
22	USB Arb Int	phub_termout1[6]	udb_intr[22]
23	USB Bus Int	phub_termout1[7]	udb_intr[23]
24	USB Endpoint[0]	phub_termout1[8]	udb_intr[24]
25	USB Endpoint Data	phub_termout1[9]	udb_intr[25]
26	Reserved	phub_termout1[10]	udb_intr[26]
27	LCD	phub_termout1[11]	udb_intr[27]
28	Reserved	phub_termout1[12]	udb_intr[28]
29	Decimator Int	phub_termout1[13]	udb_intr[29]
30	PHUB Error Int	phub_termout1[14]	udb_intr[30]
31	EEPROM Fault Int	phub_termout1[15]	udb_intr[31]

6.2.1 Power Modes

PSoC 3 devices have four different power modes, as shown in Table 6-2 and Table 6-3. The power modes allow a design to easily provide required functionality and processing power while simultaneously minimizing power consumption and maximizing battery life in low-power and portable devices.

PSoC 3 power modes, in order of decreasing power consumption are:

- Active
- Alternate Active
- Sleep
- Hibernate

Active is the main processing mode. Its functionality is configurable. Each power controllable subsystem is enabled or disabled by using separate power configuration template registers. In alternate active mode, fewer subsystems are enabled, reducing power. In sleep mode most resources are disabled regardless of the template settings. Sleep mode is optimized to provide timed sleep intervals and RTC functionality. The lowest power mode is hibernate, which retains register and SRAM state, but no clocks, and allows wakeup only from I/O pins. Figure 6-5 illustrates the allowable transitions between power modes. Sleep and hibernate modes should not be entered until all VDDIO supplies are at valid voltage levels.

Table 6-2. Power Modes

Power Modes	Description	Entry Condition	Wakeup Source	Active Clocks	Regulator
Active	Primary mode of operation, all peripherals available (programmable)	Wakeup, reset, manual register entry	Any interrupt	Any (programmable)	All regulators available. Digital and analog regulators can be disabled if external regulation used.
Alternate Active	Similar to Active mode, and is typically configured to have fewer peripherals active to reduce power. One possible configuration is to use the UDBs for processing, with the CPU turned off	Manual register entry	Any interrupt	Any (programmable)	All regulators available. Digital and analog regulators can be disabled if external regulation used.
Sleep	All subsystems automatically disabled	Manual register entry	Comparator, PICU, I^2C, RTC, CTW, LVD	ILO/kHzECO	Both digital and analog regulators buzzed. Digital and analog regulators can be disabled if external regulation used.
Hibernate	All subsystems automatically disabled Lowest power consuming mode with all peripherals and internal regulators disabled, except hibernate regulator is enabled Configuration and memory contents retained	Manual register entry	PICU		Only hibernate regulator active.

Table 6-3. Power Modes Wakeup Time and Power Consumption

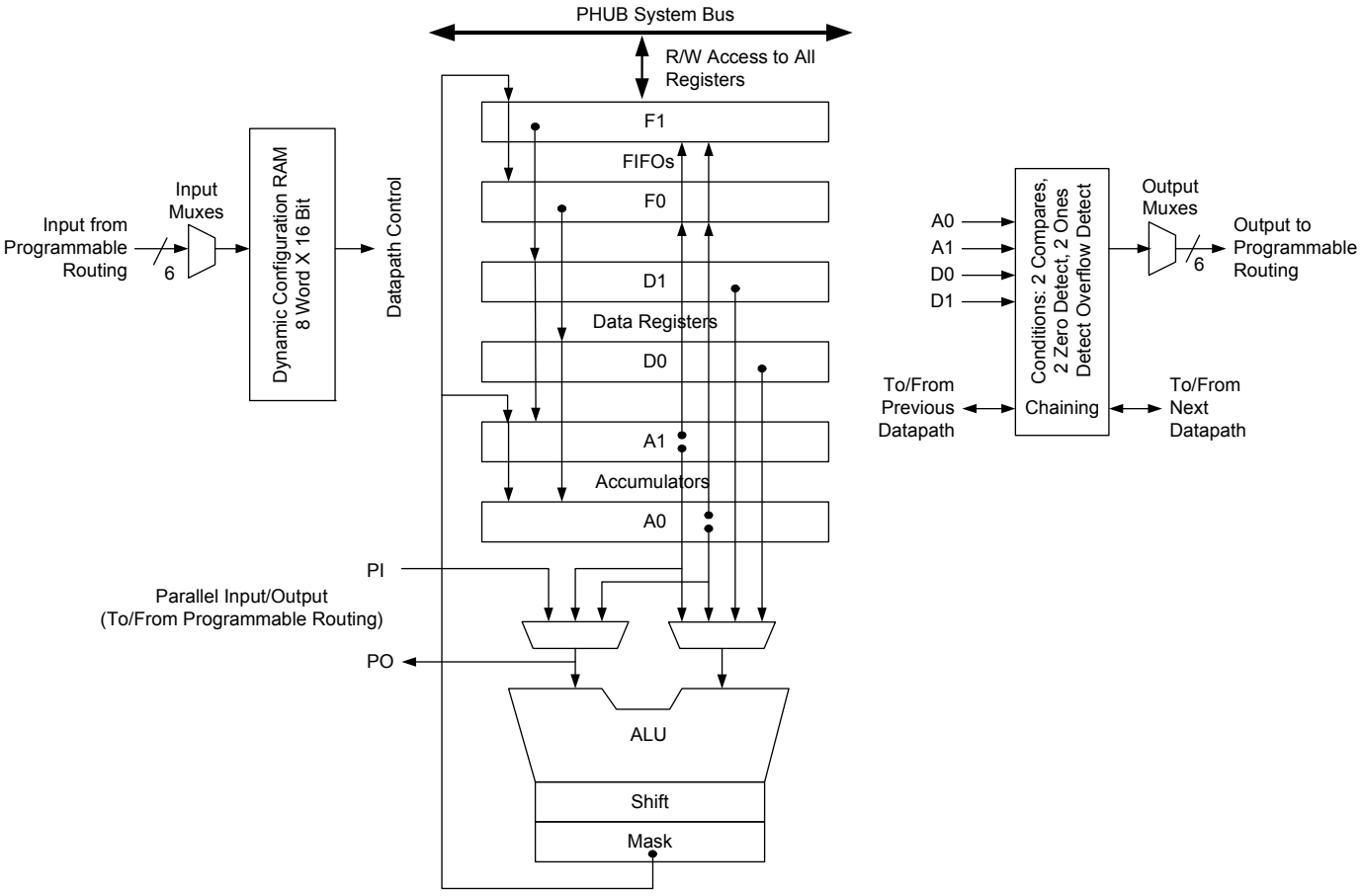
Sleep Modes	Wakeup Time	Current (typ)	Code Execution	Digital Resources	Analog Resources	Clock Sources Available	Wakeup Sources	Reset Sources
Active	–	1.2 mA[11]	Yes	All	All	All	–	All
Alternate Active	–	–	User defined	All	All	All	–	All
Sleep	<15 µs	1 µA	No	I^2C	Comparator	ILO/kHzECO	Comparator, PICU, I^2C, RTC, CTW, LVD	XRES, LVD, WDR
Hibernate	<100 µs	200 nA	No	None	None	None	PICU	XRES

Note
11. Bus clock off. Execute from cache at 6 MHz. See Table 11-2 on page 68.

7.2.2 Datapath Module

The datapath contains an 8-bit single cycle ALU, with associated compare and condition generation logic. This datapath block is optimized to implement embedded functions, such as timers, counters, integrators, PWMs, PRS, CRC, shifters and dead band generators and many others.

Figure 7-4. Datapath Top Level



7.2.2.1 Working Registers

The datapath contains six primary working registers, which are accessed by CPU firmware or DMA during normal operation.

Table 7-1. Working Datapath Registers

Name	Function	Description
A0 and A1	Accumulators	These are sources and sinks for the ALU and also sources for the compares.
D0 and D1	Data Registers	These are sources for the ALU and sources for the compares.
F0 and F1	FIFOs	These are the primary interface to the system bus. They can be a data source for the data registers and accumulators or they can capture data from the accumulators or ALU. Each FIFO is four bytes deep.

7.2.2.2 Dynamic Configuration RAM

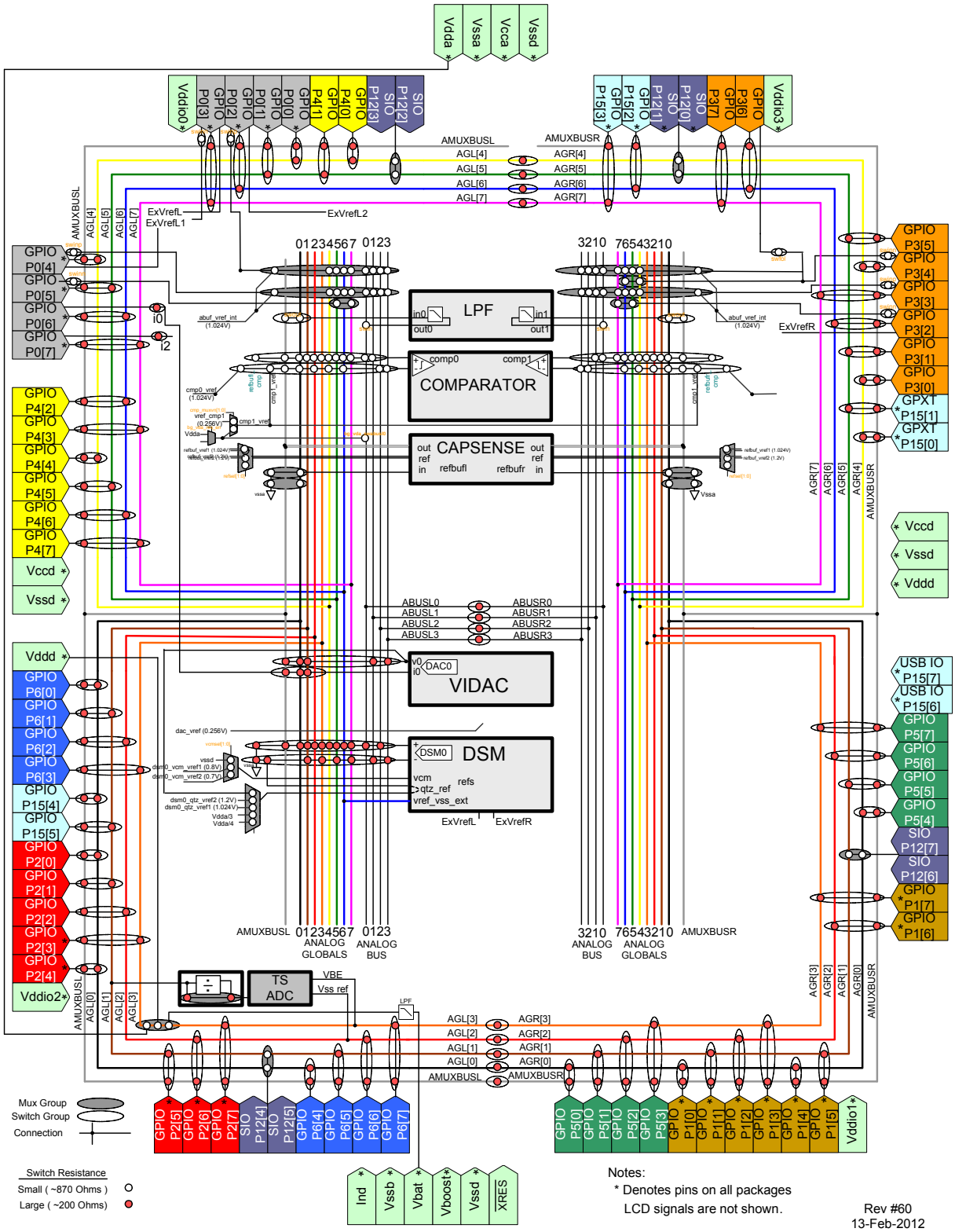
Dynamic configuration is the ability to change the datapath function and internal configuration on a cycle-by-cycle basis, under sequencer control. This is implemented using the 8-word × 16-bit configuration RAM, which stores eight unique 16-bit wide configurations. The address input to this RAM controls the sequence, and can be routed from any block connected to the UDB routing matrix, most typically PLD logic, I/O pins, or from the outputs of this or other datapath blocks.

ALU

The ALU performs eight general purpose functions. They are:

- Increment
- Decrement
- Add
- Subtract
- Logical AND
- Logical OR
- Logical XOR
- Pass, used to pass a value through the ALU to the shift register, mask, or another UDB register

Figure 8-2. CY8C32 Analog Interconnect



To preserve detail of this figure, this figure is best viewed with a PDF display program or printed on a 11" × 17" paper.

More information on output formats is provided in the Technical Reference Manual.

8.2.3 Start of Conversion Input

The SoC signal is used to start an ADC conversion. A digital clock or UDB output can be used to drive this input. It can be used when the sampling period must be longer than the ADC conversion time or when the ADC must be synchronized to other hardware. This signal is optional and does not need to be connected if ADC is running in a continuous mode.

8.2.4 End of Conversion Output

The EoC signal goes high at the end of each ADC conversion. This signal may be used to trigger either an interrupt or DMA request.

8.3 Comparators

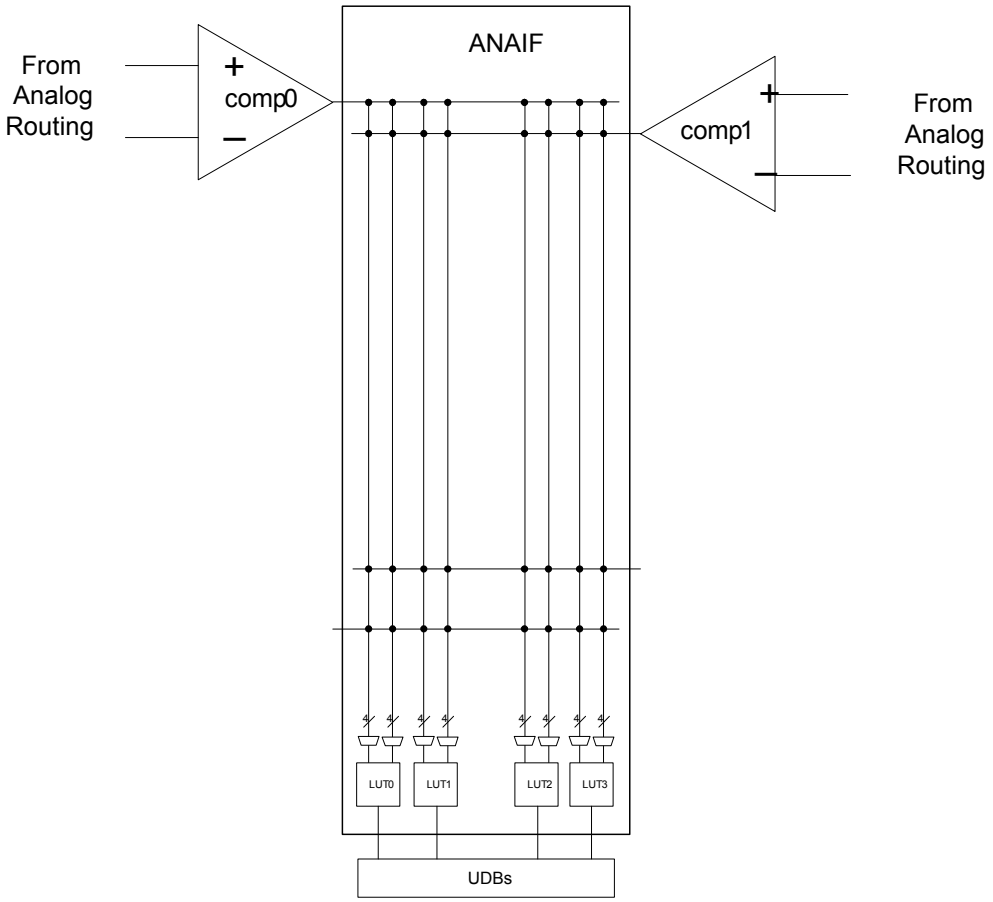
The CY8C32 family of devices contains two comparators in a device. Comparators have these features:

- Input offset factory trimmed to less than 5 mV
- Rail-to-rail common mode input range (VSSA to VDDA)
- Speed and power can be traded off by using one of three modes: fast, slow, or ultra low-power
- Comparator outputs can be routed to lookup tables to perform simple logic functions and then can also be routed to digital blocks
- The positive input of the comparators may be optionally passed through a low pass filter. Two filters are provided
- Comparator inputs can be connections to GPIO or DAC output

8.3.1 Input and Output Interface

The positive and negative inputs to the comparators come from the analog global buses, the analog mux line, the analog local bus and precision reference through multiplexers. The output from each comparator could be routed to any of the two input LUTs. The output of that LUT is routed to the UDB Digital System Interface.

Figure 8-5. Analog Comparator



8.4.4 LCD DAC

The LCD DAC generates the contrast control and bias voltage for the LCD system. The LCD DAC produces up to five LCD drive voltages plus ground, based on the selected bias ratio. The bias voltages are driven out to GPIO pins on a dedicated LCD bias bus, as required.

8.5 CapSense

The CapSense system provides a versatile and efficient means for measuring capacitance in applications such as touch sense buttons, sliders, proximity detection, etc. The CapSense system uses a configuration of system resources, including a few hardware functions primarily targeted for CapSense. Specific resource usage is detailed in each CapSense component in PSoC Creator.

A capacitive sensing method using a delta-sigma modulator (CSD) is used. It provides capacitance sensing using a switched capacitor technique with a delta-sigma modulator to convert the sensing current to a digital code.

8.6 Temp Sensor

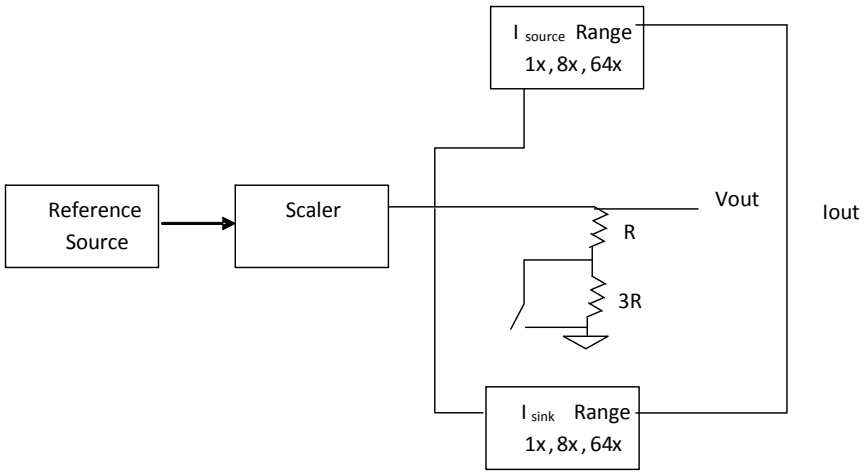
Die temperature is used to establish programming parameters for writing flash. Die temperature is measured using a dedicated sensor based on a forward biased transistor. The temperature sensor has its own auxiliary ADC.

8.7 DAC

The CY8C32 parts contain a Digital to Analog Converter (DAC). The DAC is 8-bit and can be configured for either voltage or current output. The DAC supports CapSense, power supply regulation, and waveform generation. The DAC has the following features:

- Adjustable voltage or current output in 255 steps
- Programmable step size (range selection)
- Eight bits of calibration to correct ± 25 percent of gain error
- Source and sink option for current output
- High and low speed / power modes
- 8 Msps conversion rate for current output
- 1 Msps conversion rate for voltage output
- Monotonic in nature
- Data and strobe inputs can be provided by the CPU or DMA, or routed directly from the DSI
- Dedicated low-resistance output pin for high-current mode

Figure 8-7. DAC Block Diagram



8.7.1 Current DAC

The current DAC (IDAC) can be configured for the ranges 0 to 31.875 µA, 0 to 255 µA, and 0 to 2.04 mA. The IDAC can be configured to source or sink current.

8.7.2 Voltage DAC

For the voltage DAC (VDAC), the current DAC output is routed through resistors. The two ranges available for the VDAC are 0 to 1.02 V and 0 to 4.08 V. In voltage mode any load connected to the output of a DAC should be purely capacitive (the output of the VDAC is not buffered).

Figure 11-11. Efficiency vs V_{BAT}, L_{BOOST} = 4.7 µH [35]

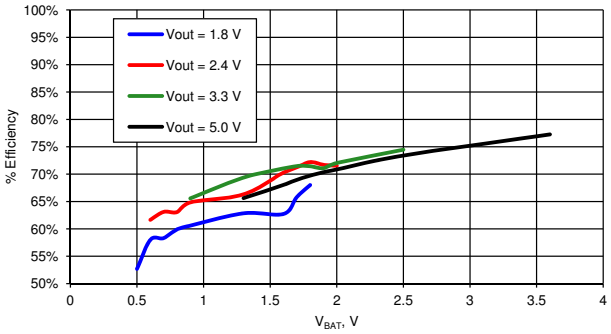


Figure 11-12. Efficiency vs V_{BAT}, L_{BOOST} = 10 µH [35]

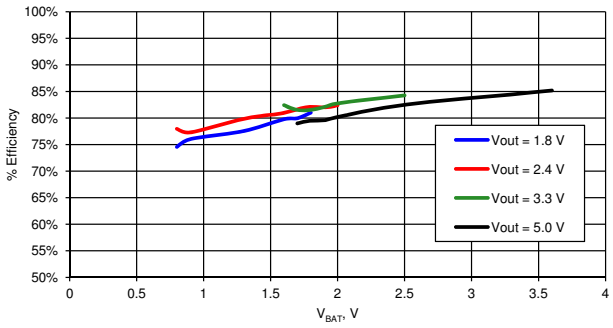


Figure 11-13. Efficiency vs V_{BAT}, L_{BOOST} = 22 µH [35]

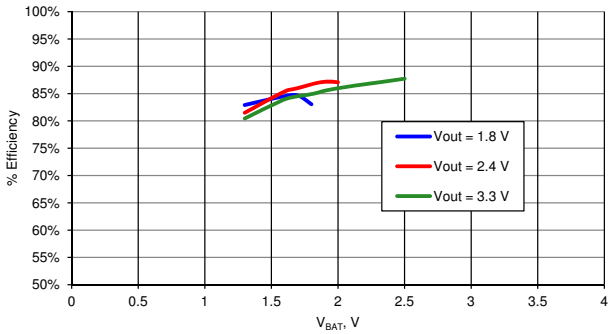
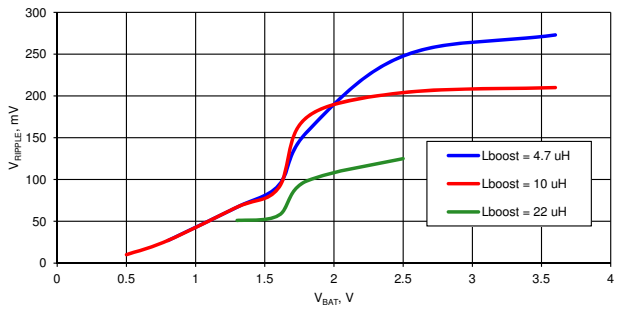


Figure 11-14. V_{RIPPLE} vs V_{BAT} [35]



Note
35. Typical example. Actual values may vary depending on external component selection, PCB layout, and other design parameters.

Figure 11-17. SIO Output High Voltage and Current, Unregulated Mode

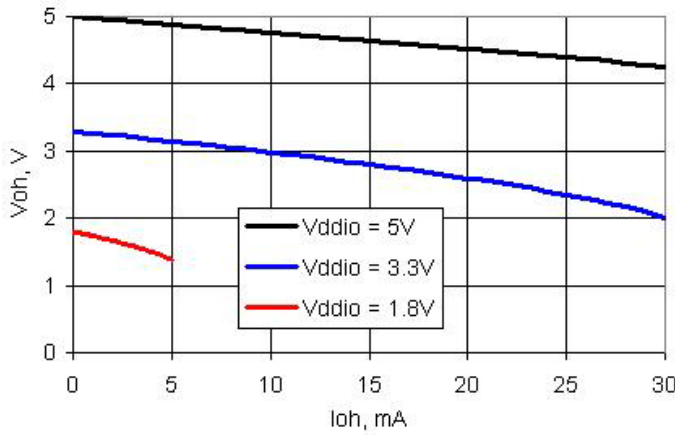


Figure 11-18. SIO Output Low Voltage and Current, Unregulated Mode

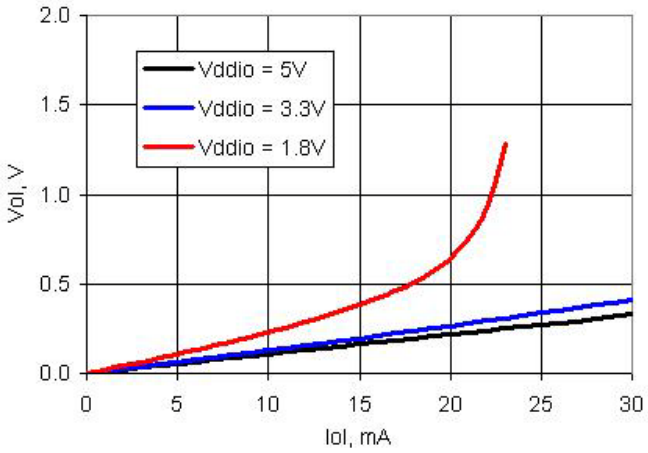


Figure 11-19. SIO Output High Voltage and Current, Regulated Mode

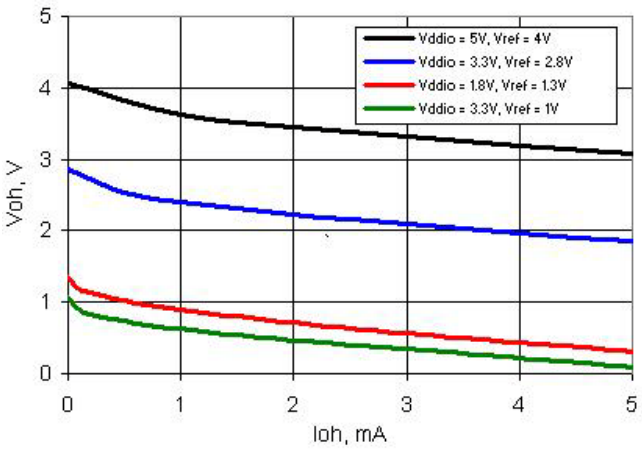


Table 11-12. SIO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
TriseF	Rise time in Fast Strong Mode (90/10%)[41]	Cload = 25 pF, V_{DDIO} = 3.3 V	–	–	12	ns
TfallF	Fall time in Fast Strong Mode (90/10%)[41]	Cload = 25 pF, V_{DDIO} = 3.3 V	–	–	12	ns
TriseS	Rise time in Slow Strong Mode (90/10%)[41]	Cload = 25 pF, V_{DDIO} = 3.0 V	–	–	75	ns
TfallS	Fall time in Slow Strong Mode (90/10%)[41]	Cload = 25 pF, V_{DDIO} = 3.0 V	–	–	60	ns

Note
41. Based on device characterization (Not production tested).

Figure 11-28. IDAC DNL vs Input Code, Range = 255 µA, Source Mode

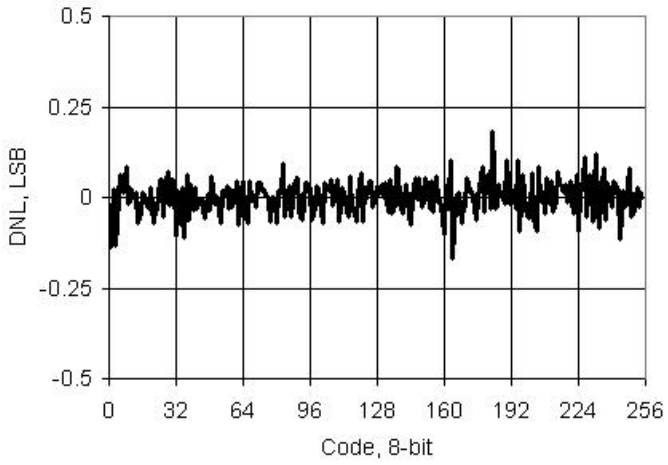


Figure 11-29. IDAC DNL vs Input Code, Range = 255 µA, Sink Mode

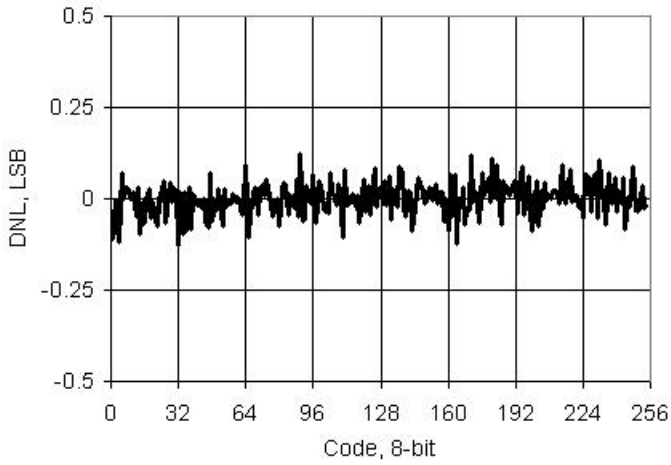


Figure 11-30. IDAC INL vs Temperature, Range = 255 µA, High speed mode

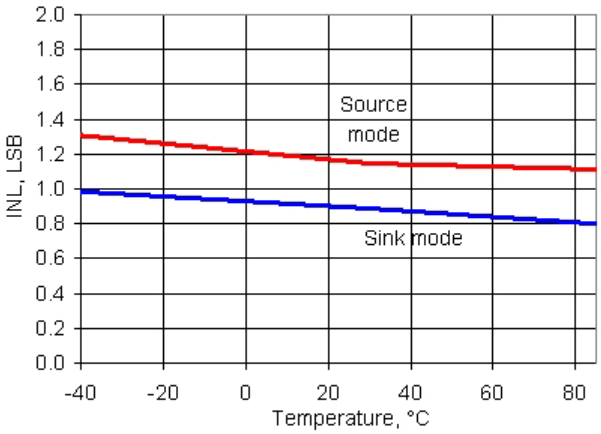
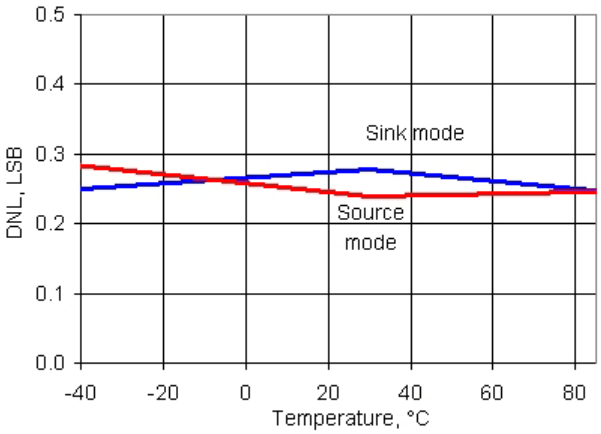


Figure 11-31. IDAC DNL vs Temperature, Range = 255 µA, High speed mode



11.5.6 Voltage Digital to Analog Converter (VDAC)

See the VDAC component datasheet in PSoC Creator for full electrical specifications and APIs.

Unless otherwise specified, all charts and graphs show typical values.

Table 11-28. VDAC DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Resolution		–	8	–	bits
INL1	Integral nonlinearity	1 V scale	–	±2.1	±2.5	LSB
INL4	Integral nonlinearity[52]	4 V scale	–	±2.1	±2.5	LSB
DNL1	Differential nonlinearity	1 V scale	–	±0.3	±1	LSB
DNL4	Differential nonlinearity[52]	4 V scale	–	±0.3	±1	LSB
Rout	Output resistance	1 V scale	–	4	–	kΩ
		4 V scale	–	16	–	kΩ
V_{OUT}	Output voltage range, code = 255	1 V scale	–	1.02	–	V
		4 V scale, V_{DDA} = 5 V	–	4.08	–	V
	Monotonicity		–	–	Yes	–
V_{OS}	Zero scale error		–	0	±0.9	LSB
Eg	Gain error	1 V scale	–	–	±2.5	%
		4 V scale	–	–	±2.5	%
TC_Eg	Temperature coefficient, gain error	1 V scale	–	–	0.03	%FSR / °C
		4 V scale	–	–	0.03	%FSR / °C
I_{DD}	Operating current	Low speed mode	–	–	100	µA
		High speed mode	–	–	500	µA

Figure 11-40. VDAC INL vs Input Code, 1 V Mode

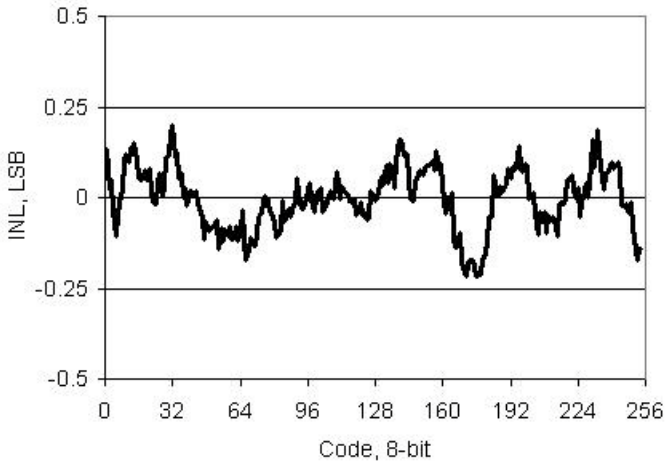
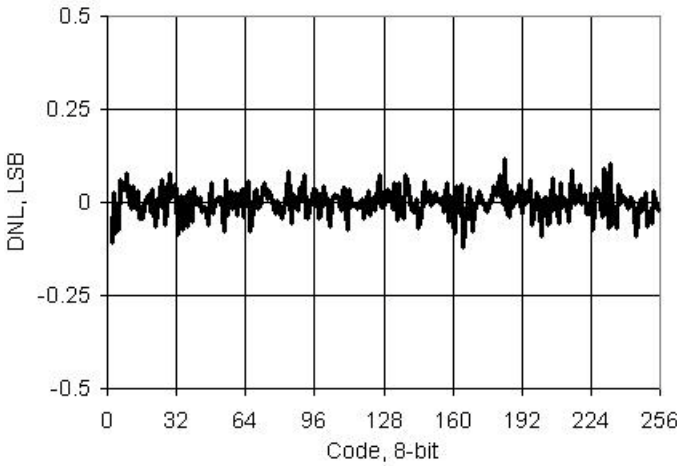


Figure 11-41. VDAC DNL vs Input Code, 1 V Mode



Note
52. Based on device characterization (Not production tested).

11.6.6 USB

Table 11-43. USB DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{USB_5}	Device supply (V_{DDD}) for USB operation	USB configured, USB regulator enabled	4.35	–	5.25	V
$V_{USB\_3.3}$		USB configured, USB regulator bypassed	3.15	–	3.6	V
V_{USB_3}		USB configured, USB regulator bypassed[54]	2.85	–	3.6	V
$I_{USB\_Configured}$	Device supply current in device active mode, bus clock and IMO = 24 MHz	V_{DDD} = 5 V, F_{CPU} = 1.5 MHz	–	10	–	mA
		V_{DDD} = 3.3 V, F_{CPU} = 1.5 MHz	–	8	–	mA
$I_{USB\_Suspended}$	Device supply current in device sleep mode	V_{DDD} = 5 V, connected to USB host, PICU configured to wake on USB resume signal	–	0.5	–	mA
		V_{DDD} = 5 V, disconnected from USB host	–	0.3	–	mA
		V_{DDD} = 3.3 V, connected to USB host, PICU configured to wake on USB resume signal	–	0.5	–	mA
		V_{DDD} = 3.3 V, disconnected from USB host	–	0.3	–	mA

11.6.7 Universal Digital Blocks (UDBs)

PSoC Creator provides a library of pre-built and tested standard digital peripherals (UART, SPI, LIN, PRS, CRC, timer, counter, PWM, AND, OR, and so on) that are mapped to the UDB array. See the component datasheets in PSoC Creator for full AC/DC specifications, APIs, and example code.

Table 11-44. UDB AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Datapath Performance						
F_{MAX_TIMER}	Maximum frequency of 16-bit timer in a UDB pair		–	–	50.01	MHz
F_{MAX_ADDER}	Maximum frequency of 16-bit adder in a UDB pair		–	–	50.01	MHz
F_{MAX_CRC}	Maximum frequency of 16-bit CRC/PRS in a UDB pair		–	–	50.01	MHz
PLD Performance						
F_{MAX_PLD}	Maximum frequency of a two-pass PLD function in a UDB pair		–	–	50.01	MHz
Clock to Output Performance						
t_{CLK_OUT}	Propagation delay for clock in to data out, see Figure 11-52 on page 99.	25 °C, $V_{DDD} \geq 2.7$ V	–	20	25	ns
t_{CLK_OUT}	Propagation delay for clock in to data out, see Figure 11-52 on page 99.	Worst-case placement, routing, and pin selection	–	–	55	ns

Note
54. Rise/fall time matching (TR) not guaranteed, see USB Driver AC Specifications on page 83.

11.7.2 EEPROM

Table 11-47. EEPROM DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage		1.71	–	5.5	V

Table 11-48. EEPROM AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{WRITE}	Single row erase/write cycle time		–	10	20	ms
	EEPROM data retention time, retention period measured from last erase cycle	Average ambient temp, $T_A \le 25$ °C, 1M erase/program cycles	20	–	–	years
		Average ambient temp, $T_A \le 55$ °C, 100 K erase/program cycles	20	–	–	
		Average ambient temp. $T_A \le 85$ °C, 10 K erase/program cycles	10	–	–	

11.7.3 Nonvolatile Latches (NVL))

Table 11-49. NVL DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage	V_{DDD} pin	1.71	–	5.5	V

Table 11-50. NVL AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	NVL endurance	Programmed at 25 °C	1K	–	–	program/ erase cycles
		Programmed at 0 °C to 70 °C	100	–	–	program/ erase cycles
	NVL data retention time	Average ambient temp. $T_A \le 55$ °C	20	–	–	years
		Average ambient temp. $T_A \le 85$ °C	10	–	–	years

11.7.4 SRAM

Table 11-51. SRAM DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{SRAM}	SRAM retention voltage		1.2	–	–	V

Table 11-52. SRAM AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F_{SRAM}	SRAM operating frequency		DC	–	50.01	MHz

11.8.5 SWD Interface

Figure 11-58. SWD Interface Timing

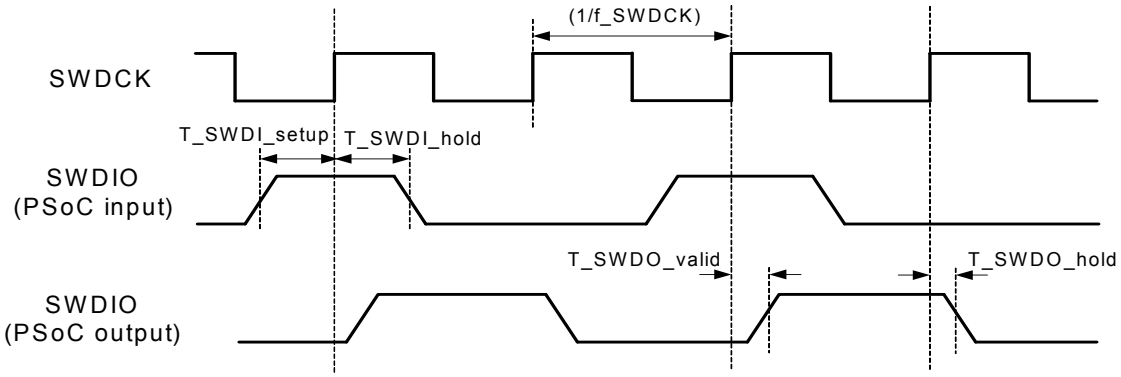


Table 11-63. SWD Interface AC Specifications[67]

Parameter	Description	Conditions	Min	Typ	Max	Units
f_SWDCK	SWDCLK frequency	3.3 V ≤ V_{DDD} ≤ 5 V	–	–	14[68]	MHz
		1.71 V ≤ V_{DDD} < 3.3 V	–	–	7[68]	MHz
		1.71 V ≤ V_{DDD} < 3.3 V, SWD over USBIO pins	–	–	5.5[68]	MHz
T_SWDI_setup	SWDIO input setup before SWDCK high	T = 1/f_SWDCK max	T/4	–	–	
T_SWDI_hold	SWDIO input hold after SWDCK high	T = 1/f_SWDCK max	T/4	–	–	
T_SWDO_valid	SWDCK high to SWDIO output	T = 1/f_SWDCK max	–	–	2T/5	

11.8.6 SWV Interface

Table 11-64. SWV Interface AC Specifications[30]

Parameter	Description	Conditions	Min	Typ	Max	Units
	SWV mode SWV bit rate		–	–	33	Mbit

11.9 Clocking

Specifications are valid for –40 °C ≤ T_A ≤ 85 °C and T_J ≤ 100 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.9.1 Internal Main Oscillator

Table 11-65. IMO DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Supply current					
	24 MHz – USB mode	With oscillator locking to USB bus	–	–	500	µA
	24 MHz – non USB mode		–	–	300	µA
	12 MHz		–	–	200	µA
	6 MHz		–	–	180	µA
	3 MHz		–	–	150	µA

Notes
67. Based on device characterization (Not production tested).
68. f_SWDCK must also be no more than 1/3 CPU clock frequency.

Figure 13-1. 48-pin (300 mil) SSOP Package Outline

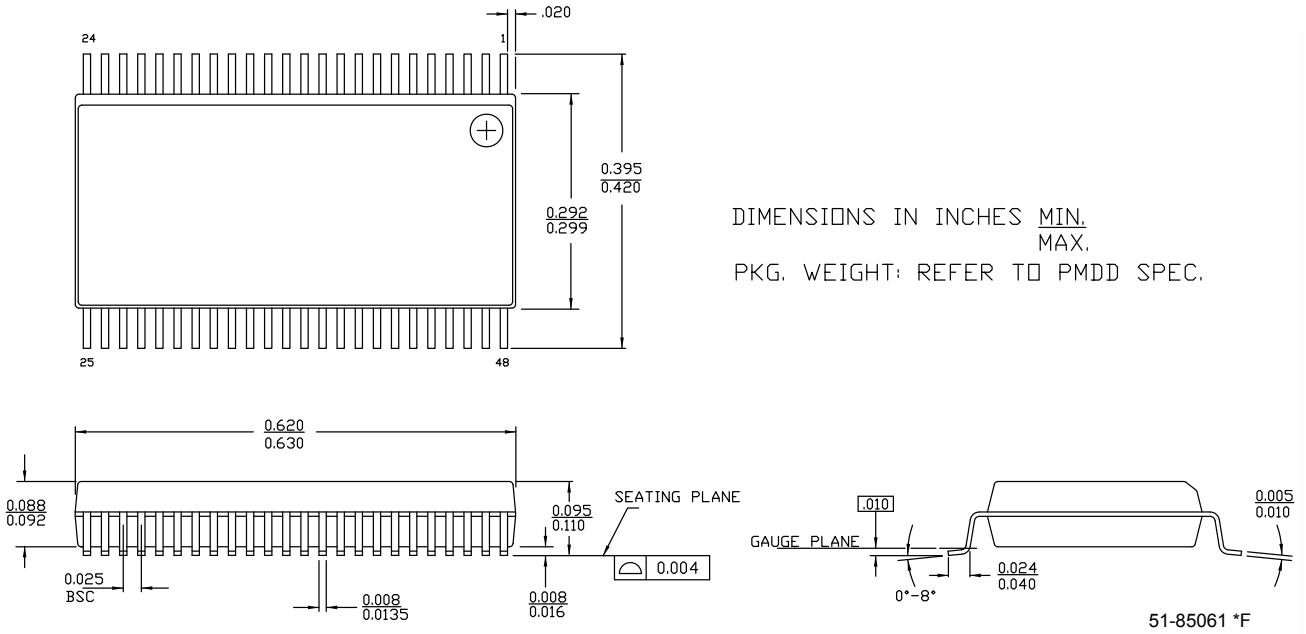
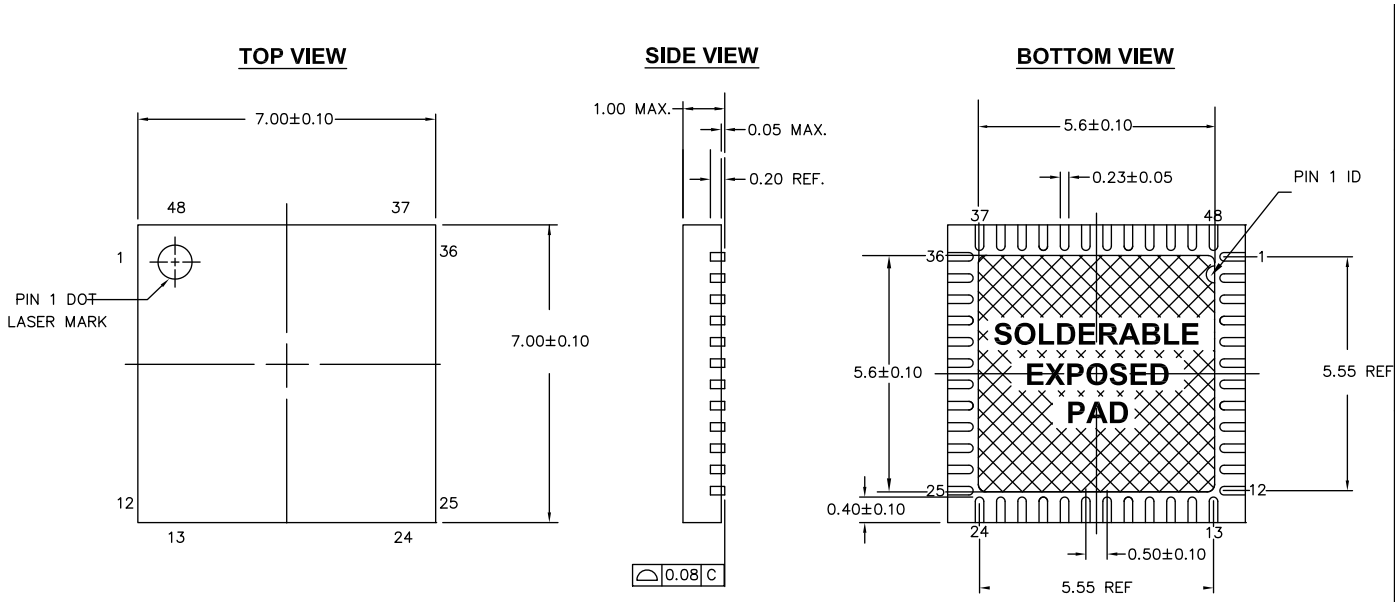


Figure 13-2. 48-pin QFN Package Outline



NOTES:

1. HATCH AREA IS SOLDERABLE EXPOSED METAL.
2. REFERENCE JEDEC#: MO-220
3. PACKAGE WEIGHT: REFER TO PMDD SPEC.
4. ALL DIMENSIONS ARE IN MM [MIN/MAX]
5. PACKAGE CODE

PART #	DESCRIPTION
LT48D	LEAD FREE

001-45616 *E

14. Acronyms

Table 14-1. Acronyms Used in this Document

Acronym	Description
abus	analog local bus
ADC	analog-to-digital converter
AG	analog global
AHB	AMBA (advanced microcontroller bus architecture) high-performance bus, an ARM data transfer bus
ALU	arithmetic logic unit
AMUXBUS	analog multiplexer bus
API	application programming interface
APSR	application program status register
ARM®	advanced RISC machine, a CPU architecture
ATM	automatic thump mode
BW	bandwidth
CAN	Controller Area Network, a communications protocol
CMRR	common-mode rejection ratio
CPU	central processing unit
CRC	cyclic redundancy check, an error-checking protocol
DAC	digital-to-analog converter, see also IDAC, VDAC
DFB	digital filter block
DIO	digital input/output, GPIO with only digital capabilities, no analog. See GPIO.
DMA	direct memory access, see also TD
DNL	differential nonlinearity, see also INL
DNU	do not use
DR	port write data registers
DSI	digital system interconnect
DWT	data watchpoint and trace
ECC	error correcting code
ECO	external crystal oscillator
EEPROM	electrically erasable programmable read-only memory
EMI	electromagnetic interference
EMIF	external memory interface
EOC	end of conversion
EOF	end of frame
EPSR	execution program status register
ESD	electrostatic discharge
ETM	embedded trace macrocell

Table 14-1. Acronyms Used in this Document *(continued)*

Acronym	Description
FIR	finite impulse response, see also IIR
FPB	flash patch and breakpoint
FS	full-speed
GPIO	general-purpose input/output, applies to a PSoC pin
HVI	high-voltage interrupt, see also LVI, LVD
IC	integrated circuit
IDAC	current DAC, see also DAC, VDAC
IDE	integrated development environment
I^2C, or IIC	Inter-Integrated Circuit, a communications protocol
IIR	infinite impulse response, see also FIR
ILO	internal low-speed oscillator, see also IMO
IMO	internal main oscillator, see also ILO
INL	integral nonlinearity, see also DNL
I/O	input/output, see also GPIO, DIO, SIO, USBIO
IPOR	initial power-on reset
IPSR	interrupt program status register
IRQ	interrupt request
ITM	instrumentation trace macrocell
LCD	liquid crystal display
LIN	Local Interconnect Network, a communications protocol.
LR	link register
LUT	lookup table
LVD	low-voltage detect, see also LVI
LVI	low-voltage interrupt, see also HVI
LVTTL	low-voltage transistor-transistor logic
MAC	multiply-accumulate
MCU	microcontroller unit
MISO	master-in slave-out
NC	no connect
NMI	nonmaskable interrupt
NRZ	non-return-to-zero
NVIC	nested vectored interrupt controller
NVL	nonvolatile latch, see also WOL
opamp	operational amplifier
PAL	programmable array logic, see also PLD
PC	program counter
PCB	printed circuit board
PGA	programmable gain amplifier

Table 14-1. Acronyms Used in this Document *(continued)*

Acronym	Description
PHUB	peripheral hub
PHY	physical layer
PICU	port interrupt control unit
PLA	programmable logic array
PLD	programmable logic device, see also PAL
PLL	phase-locked loop
PMDD	package material declaration datasheet
POR	power-on reset
PRES	precise low-voltage reset
PRS	pseudo random sequence
PS	port read data register
PSoC®	Programmable System-on-Chip™
PSRR	power supply rejection ratio
PWM	pulse-width modulator
RAM	random-access memory
RISC	reduced-instruction-set computing
RMS	root-mean-square
RTC	real-time clock
RTL	register transfer language
RTR	remote transmission request
RX	receive
SAR	successive approximation register
SC/CT	switched capacitor/continuous time
SCL	I^2C serial clock
SDA	I^2C serial data
S/H	sample and hold
SINAD	signal to noise and distortion ratio
SIO	special input/output, GPIO with advanced features. See GPIO.
SOC	start of conversion

Table 14-1. Acronyms Used in this Document *(continued)*

Acronym	Description
SOF	start of frame
SPI	Serial Peripheral Interface, a communications protocol
SR	slew rate
SRAM	static random access memory
SRES	software reset
SWD	serial wire debug, a test protocol
SWV	single-wire viewer
TD	transaction descriptor, see also DMA
THD	total harmonic distortion
TIA	transimpedance amplifier
TRM	technical reference manual
TTL	transistor-transistor logic
TX	transmit
UART	Universal Asynchronous Transmitter Receiver, a communications protocol
UDB	universal digital block
USB	Universal Serial Bus
USBIO	USB input/output, PSoC pins used to connect to a USB port
VDAC	voltage DAC, see also DAC, IDAC
WDT	watchdog timer
WOL	write once latch, see also NVL
WRES	watchdog timer reset
XRES	external reset I/O pin
XTAL	crystal

15. Reference Documents

PSoC® 3, PSoC® 5 Architecture TRM

PSoC® 3 Registers TRM